Goodness of fit via phi-divergences: a new family of test statistics

Jon A. Wellner Joint work with Leah Jager

University of Washington

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- joint work with Leah Jager, University of Washington
- Talk at Princeton University, Workshop on the Frontiers of Statistics, in honor of Peter J. Bickel
- Email: jaw@stat.washington.edu http: //www.stat.washington.edu/jaw/jaw.research.html

• Semiparametric models and Peter Bickel

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- Null hypothesis distribution theory: finite sample and limit theory
- Limit theory under alternatives and power



Robert Serfling, Peter Bickel, and Alan Karr Johns Hopkins University, June 1983





- Missing data models
- Testing and profile likelihood theory
- Semiparametric mixture model theory
- Rates of convergence via empirical process methods
- Bayes methods in semiparametric models
- Model selection methods
- Empirical likelihood
- Transformation and frailty models
- Semiparametric regression models
- Extensions to non-i.i.d. data
- Critiques and possible alternative theories

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•
$$H = \cap_x H_x$$
, $K = \cup_x K_x$

• Likelihood ratio statistic for testing H_x versus K_x :

$$\begin{split} A_{n}(x) &= \frac{\sup_{F(x)} L_{n}(F(x))}{L_{n}(F_{0}(x))} = \frac{L_{n}(\mathbb{F}_{n}(x))}{L_{n}(F_{0}(x))} \\ &= \frac{\mathbb{F}_{n}(x)^{n\mathbb{F}_{n}(x)}(1 - \mathbb{F}_{n}(x))^{n(1 - \mathbb{F}_{n}(x))}}{F_{0}(x)^{n\mathbb{F}_{n}(x)}(1 - F_{0}(x))^{n(1 - \mathbb{F}_{n}(x))}} \\ &= \left(\frac{\mathbb{F}_{n}(x)}{F_{0}(x)}\right)^{n\mathbb{F}_{n}(x)} \left(\frac{1 - \mathbb{F}_{n}(x)}{1 - F_{0}(x)}\right)^{n(1 - \mathbb{F}_{n}(x)} \end{split}$$

• Thus

$$\log \lambda_n(x) = n \mathbb{F}_n(x) \log \left(\frac{\mathbb{F}_n(x)}{F_0(x)}\right) + n(1 - \mathbb{F}_n(x)) \log \left(\frac{1 - \mathbb{F}_n(x)}{1 - F_0(x)}\right) = n K(\mathbb{F}_n(x), F_0(x))$$

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• $K(u,v) \equiv u \log \left(\frac{u}{v}\right) + (1-u) \log \left(\frac{1-u}{1-v}\right)$, Kullback - Leibler "distance" Bernoulli(u), Bernoulli(v)

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- $K(u, v) \equiv u \log \left(\frac{u}{v}\right) + (1 u) \log \left(\frac{1 u}{1 v}\right)$, Kullback - Leibler "distance" Bernoulli(u), Bernoulli(v)
- Berk-Jones (1979) test statistic:

$$R_n \equiv \sup_x n^{-1} \log \lambda_n(x) = \sup_x K(\mathbb{F}_n(x), F_0(x)).$$

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- \circ Einmahl and McKeague (2002): integral version of R_n
- Donoho and Jin (2002): supremum version of Anderson-Darling statistic
 with comparison to Berk - Jones statistic R_n

2. A new family of statistics via phi-divergences

• For $s \in \mathbb{R}$, $x \ge 0$ define

$$\phi_s(x) = \begin{cases} \frac{1-s+sx-x^s}{s(1-s)}, & s \neq 0, 1\\ x \log x - x + 1, & s = 1\\ -\log x + x - 1, & s = 0. \end{cases}$$

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• Then define

$$K_s(u,v) = v\phi_s(u/v) + (1-v)\phi_s((1-u)/(1-v)).$$

• Special cases:

$$K_{1}(u,v) = K(u,v)$$

= $u \log(u/v) + (1-u) \log((1-u)/(1-v))$
 $K_{0}(u,v) = K(v,u)$
 $K_{2}(u,v) = \frac{1}{2} \frac{(u-v)^{2}}{v(1-v)}$
 $K_{-1}(u,v) = K_{2}(v,u) = \frac{1}{2} \frac{(u-v)^{2}}{u(1-u)}$
 $K_{1/2}(u,v) = 2\{(\sqrt{u} - \sqrt{v})^{2} + (\sqrt{1-u} - \sqrt{1-v})^{2}\}$
= $4\{1 - \sqrt{uv} - \sqrt{(1-u)(1-v)}\}.$

• The new family of statistics:

$$S_n(s) = \begin{cases} \sup_{x \in \mathbb{R}} K_s(\mathbb{F}_n(x), F_0(x)), & s \ge 1\\ \sup_{x \in [X_{(1)}, X_{(n)})} K_s(\mathbb{F}_n(x), F_0(x)), & s < 1, \end{cases}$$

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• Thus, with $F_0(x) = x$,

$$S_{n}(1) = R_{n}, \qquad S_{n}(0) = \text{"reversed" Berk-Jones} \equiv \widetilde{R}_{n}$$

$$S_{n}(2) = \frac{1}{2} \sup_{x \in \mathbb{R}} \frac{(\mathbb{F}_{n}(x) - x)^{2}}{x(1 - x)}, \qquad S_{n}(-1) = \frac{1}{2} \sup_{x \in [X_{(1)}, X_{(n)})} \frac{(\mathbb{F}_{n}(x))}{\mathbb{F}_{n}(x)(1 - x)}$$

$$S_{n}(1/2)$$

$$= 4 \sup_{x \in [X_{(1)}, X_{(n)})} \{1 - \sqrt{\mathbb{F}_{n}(x)x} - \sqrt{(1 - \mathbb{F}_{n}(x))(1 - x)}\}$$



Fig. 1: $\phi_s(x)$, $s \in \{-1, -0.8, -0.6, -0.4, -0.2, 0.0, 0.2, 0.4, 0.6, 0.8, 1.0, 1.2, 1.4, 1.8, 2.0\}$







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- Let $r_n \equiv \log_2 n + (1/2) \log_3 n (1/2) \log(4\pi)$.
- Theorem. If $F = F_0$, the uniform distribution on [0, 1], then for $-1 \le s \le 2$

$$nS_n(s) - r_n \to_d Y_4$$

where $P(Y_4 \le x) = \exp(-4\exp(-x))$.





s = 1

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$$q_n^{(3)}(\alpha) = x_{\alpha,n} + c_n^2 / (2b_n^2)$$



Figure 7. Exact and approximate .95 quantiles of $nS_n(s)$, $10 \le n \le 3000$.

4. Limit theory under alternatives and power

• Theorem 1. If X_1, \ldots, X_n are i.i.d. $F \in K$ and 0 < s < 1, then

$$S_n(s) \to_{a.s.} \sup_{0 < x < 1} K_s(F(x), x) \equiv S_\infty(s, F).$$
(1)

• Theorem 2. If X_1, \ldots, X_n are i.i.d. $F \in K$ and s > 1, then (1) holds if and only if

$$\int_0^1 \{F^{-1}(u)(1 - F^{-1}(u))\}^{(1-s)/s} du < \infty.$$

• Poisson boundary distributions

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- Theorem: (Berk & Jones, 1979). If $F(x) = 1/(1 + \log(1/x))$, and X_1, \ldots, X_n are i.i.d. *F*, then

$$R_n = S_n(1) \to_d 1/U \stackrel{d}{=} \sup_{t>0} \frac{\mathbb{N}(t)}{t}$$

where $U \sim U(0,1)$, \mathbb{N} is a standard Poisson process.

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Generalization: let

$$F_s(x) = \begin{cases} (1 + \frac{x^{1-s} - 1}{s-1})^{-1/s}, & 1 < s < \infty, \\ (1 + \log(1/x))^{-1}, & s = 1, \\ (1 - s(x^{s-1} - 1))^{1/s}, & s < 0. \end{cases}$$

Theorem. (Poisson boundaries for s ≥ 1 and s < 0).
(i) Fix s ≥ 1 and suppose that X₁,..., X_n are i.i.d. F_s. Then

$$S_n(s) \to_d \frac{1}{s} \left(\sup_{t>0} \frac{\mathbb{N}(t)}{t} \right)^s \stackrel{d}{=} \frac{1}{sU^s}$$

(ii) Fix s < 0 and suppose that X_1, \ldots, X_n are i.i.d. F_s . Then

$$S_n(s) \to_d \frac{1}{1-s} \left(\sup_{t \ge S_1} \frac{t}{\mathbb{N}(t)} \right)^{-s}$$

where $S_1 = E_1$ is the first jump point of \mathbb{N} .



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- test H: $G = \Phi$, the standard N(0,1) d.f. versus $H_1: G = (1 \epsilon)\Phi + \epsilon\Phi(\cdot \mu)$, and, in particular, against

$$H_1^{(n)}: G = (1 - \epsilon_n)\Phi + \epsilon_n\Phi(\cdot - \mu_n)$$

for $\epsilon_n = n^{-\beta}$, $\mu_n = \sqrt{2r \log n}$ $1/2 < \beta < 1, 0 < r < 1.$ • transform to $X_i \equiv 1 - \Phi(Y_i) \in [0, 1]$ i.i.d.

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• Test statistics: Donoho-Jin: Berk-Jones $R_n = S_n(1)$ and

$$HC_n^* \equiv \sup_{X_{(1)} \le x < X_{([n/2])}} \frac{\sqrt{n}(\mathbb{F}_n(x) - x)}{\sqrt{x(1 - x)}}$$

$$\equiv \text{Tukey's "higher criticism statistic"}$$

• Define the optimal detection boundary $\rho^*(\beta)$ by

$$\rho^*(\beta) = \begin{cases} \beta - 1/2, & 1/2 < \beta \le 3/4 \\ (1 - \sqrt{1 - \beta})^2, & 3/4 < \beta < 1 \end{cases}$$

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• Theorem: (Donoho - Jin, 2004). For $r > \rho^*(\beta)$ the tests based on HC_n^* and $R_n = S_n(1)$ are size and power consistent for testing H_0 versus $H_1^{(n)}$.

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- Theorem: (Jager Wellner, 2006). For $r > \rho^*(\beta)$ the tests based on $S_n(s)$ with $-1 \le s \le 2$ are size and power consistent for testing H_0 versus $H_1^{(n)}$.





Figure 9. Separation plots: $n = 5 \times 10^5$, r = .15, $\beta = 1/2$ Smoothed histograms of reps = 200 of the statistics under the null hypothesis and the the alternative hypothesis

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• Current estimate: first sign change of $Li(x) - \pi(x)$ before 10^{316} .